

flow BOOST 0

1200V/40A

Features

- High efficiency dual boost
- Ultra fast switching frequency
- Low Inductance Layout
- 1200V IGBT and 1200V SiC diode
- PressFiT option

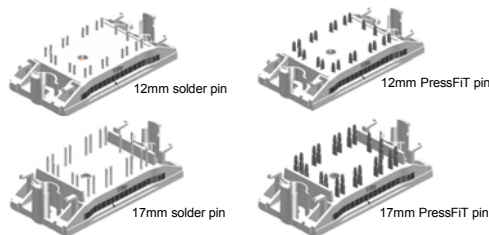
Target Applications

- solar inverter

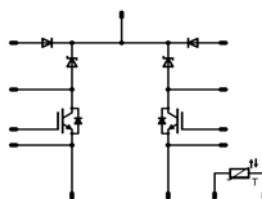
Types

- V23990-P629-F62-PM
- V23990-P629-F629-PM
- V23990-P629-F628Y-PM
- V23990-P629-F629Y-PM

flow0 12mm and 17mm housing



Schematic



Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
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Bypass diode

Repetitive peak reverse voltage	V _{RRM}		1600	V
DC forward current	I _{FAV}	DC current T _h =80°C T _c =80°C	34 47	A
Surge forward current	I _{FSM}	t _p =10ms T _j =25°C	220	A
I ² t-value	I ² t		240	A ² s
Power dissipation per Diode	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	41 62	W
Maximum Junction Temperature	T _{jmax}		150	°C

Boost IGBT

Collector-emitter break down voltage	V _{CE}		1200	V
DC collector current	I _C	T _j =T _{jmax} T _h =80°C T _c =80°C	35 48	A
Repetitive peak collector current	I _{Cpulse}	t _p limited by T _{jmax}	120	A
Power dissipation per IGBT	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	108 164	W
Gate-emitter peak voltage	V _{GE}		±25	V
Short circuit ratings	t _{SC} V _{CC}	T _j ≤150°C V _{GE} =15V	10 600	μs V
Maximum Junction Temperature	T _{jmax}		150	°C

Maximum Ratings

$T_j=25^{\circ}\text{C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
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Boost IGBT Protection Diode

Peak Repetitive Reverse Voltage	V_{RRM}	$T_j=25^{\circ}\text{C}$	1200	V
DC forward current	I_F	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	7 9	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	6	A
Power dissipation per Diode	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	24 37	W
Maximum Junction Temperature	T_{jmax}		150	$^{\circ}\text{C}$

Boost FRED

Peak Repetitive Reverse Voltage	V_{RRM}	$T_j=25^{\circ}\text{C}$	1200	V
DC forward current	I_F	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	24 28	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	90	A
Power dissipation	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	90 136	W
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

Thermal Properties

Storage temperature	T_{stg}		-40...+125	$^{\circ}\text{C}$
Operation temperature under switching condition	T_{op}		-40...+($T_{jmax} - 25$)	$^{\circ}\text{C}$

Insulation Properties

Insulation voltage	V_{is}	$t=2s$ DC voltage	4000	V
Creepage distance			min 12,7	mm
Clearance			min 12,7	mm

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
			V _{GE} [V] or V _{GS} [V]	V _r [V] or V _{CE} [V] or V _{DS} [V]	I _C [A] or I _F [A] or I _o [A]	T _j	Min	Typ	Max	
Bypass diode										
Forward voltage	V _{to}				25	T _j =25°C T _j =125°C	0.8	1.13 1.09	1.9	V
Threshold voltage (for power loss calc. only)	V _{to}					T _j =25°C T _j =125°C		0.93 0.8		V
Slope resistance (for power loss calc. only)	r _t				25	T _j =25°C T _j =125°C		0.0081 0.0112		Ω
Reverse current	I _r			1600		T _j =25°C T _j =145°C			0.05	mA
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal foil thickness=76um						1.71		K/W
Thermal resistance chip to case per chip	R _{thJC}	Kunze foil KU- ALF5						1		
Boost IGBT										
Gate emitter threshold voltage	V _{GE(th)}		VCE=VGE		0.025	T _j =25°C T _j =125°C	3.5	5.5	7.5	V
Collector-emitter saturation voltage	V _{CE(sat)}		15		40	T _j =25°C T _j =125°C	1	2.6 2.9	3.5	V
Collector-emitter cut-off	I _{CES}		0	1200		T _j =25°C T _j =125°C			1	mA
Gate-emitter leakage current	I _{GES}		25			T _j =25°C T _j =125°C			300	nA
Integrated Gate resistor	R _{gint}							none none		Ω
Turn-on delay time	t _{d(on)}	Rgoff=4 Ω Rgon=4 Ω	±15	600	40	T _j =25°C T _j =125°C		25 25		ns
Rise time	t _r					T _j =25°C T _j =125°C		13 35		
Turn-off delay time	t _{d(off)}					T _j =25°C T _j =125°C		172 202		
Fall time	t _f					T _j =25°C T _j =125°C		13 35		
Turn-on energy loss per pulse	E _{on}					T _j =25°C T _j =125°C		0.41 0.513		mWs
Turn-off energy loss per pulse	E _{off}					T _j =25°C T _j =125°C		0.846 1.661		
Input capacitance	C _{ies}	f=1MHz	0	30		T _j =25°C		3200		pF
Output capacitance	C _{oss}							370		
Reverse transfer capacitance	C _{rss}							125		
Gate charge	Q _{Gate}		15	600	40	T _j =25°C		25		nC
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal foil thickness=76um						0.65		K/W
Thermal resistance chip to case per chip	R _{thJC}	Kunze foil KU- ALF5						0.43		
Boost IGBT Protection Diode										
Diode forward voltage	V _F				3	T _j =25°C T _j =125°C	0.7	1.8 1.63	2.4	V
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal foil thickness=76um						2.87		K/W
Thermal resistance chip to case per chip	R _{thJC}	Kunze foil KU- ALF5						1.89		
Boost FRED										
Forward voltage	V _F				40	T _j =25°C T _j =150°C	1	2.74 3.01	1.9	V
Reverse leakage current	I _{rm}		±15	600	40	T _j =25°C T _j =175°C			600	μA
Peak recovery current	I _{RRM}	Rgon=4 Ω	±15	600	40	T _j =25°C T _j =150°C		23.95 22.64		A
Reverse recovery time	t _{rr}					T _j =25°C T _j =150°C		8.6 9.4		ns
Reverse recovery charge	Q _{rr}					T _j =25°C T _j =150°C		0.1 0.1115		μC
Reverse recovered energy	E _{rec}					T _j =25°C T _j =150°C		0.004 0.011		mWs
Peak rate of fall of recovery current	di(rec)max /dt					T _j =25°C T _j =150°C		10933 7266		A/μs
Thermal resistance chip to heatsink per chip	R _{thJH}					Thermal foil thickness=76um				
Thermal resistance chip to case per chip	R _{thJC}	Kunze foil KU- ALF5						0.70		

Characteristic Values

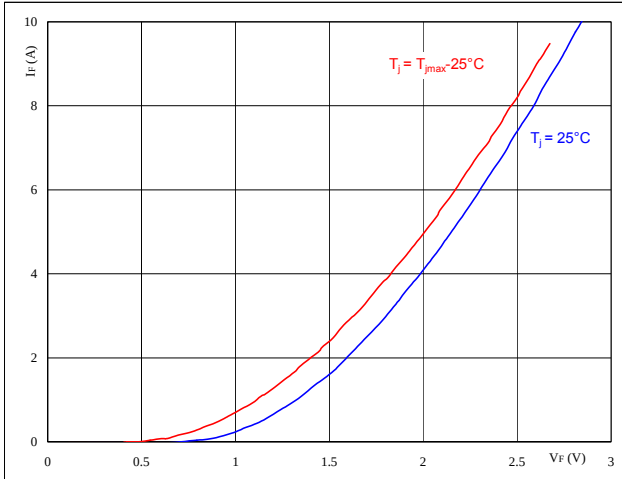
Parameter	Symbol	Conditions					Value			Unit
			$V_{GE}[V]$ or $V_{GS}[V]$	$V_i[V]$ or $V_{CE}[V]$ or $V_{DS}[V]$	$I_C[A]$ or $I_F[A]$ or $I_D[A]$	T_j	Min	Typ	Max	
Thermistor										
Rated resistance	R					$T=25^{\circ}C$		22		k Ω
Deviation of R25	$\Delta R/R$	R25=22K Ω				$T=25^{\circ}C$	-3%		+3%	%/K
Power dissipation	P					$T=25^{\circ}C$			200	%/K
Power dissipation constant						$T_j=25^{\circ}C$		2		mW
B-value	B(25/50)	Tol. $\pm 3\%$				$T_j=25^{\circ}C$		3950		K
B-value	B(25/100)	Tol. $\pm 3\%$				$T_j=25^{\circ}C$		3998		K
Vincotech NTC Reference										K

Boost IGBT Protection Diode

Figure 1 Boost IGBT Protection Diode

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

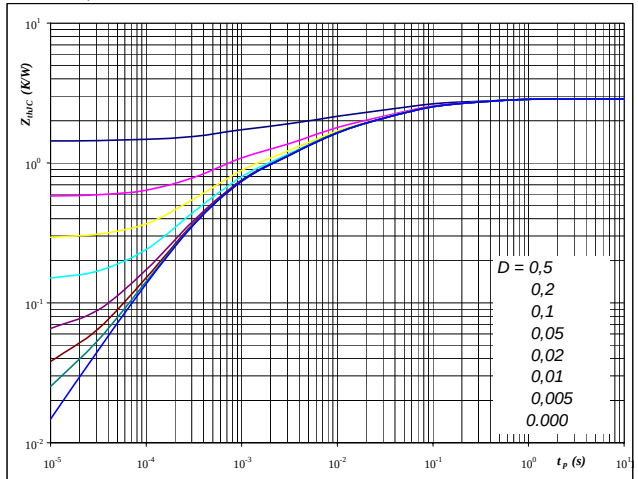


At
 $t_p = 250 \mu s$

Figure 2 Boost IGBT Protection Diode

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$

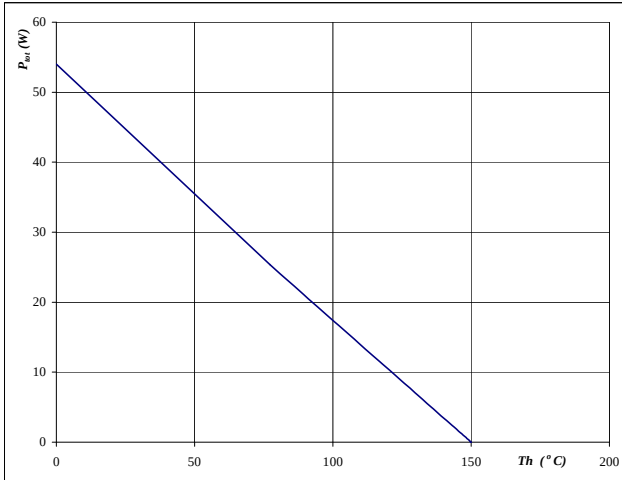


At
D = t_p / T
 $R_{thJH} = 2.87 \text{ K/W}$

Figure 3 Boost IGBT Protection Diode

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

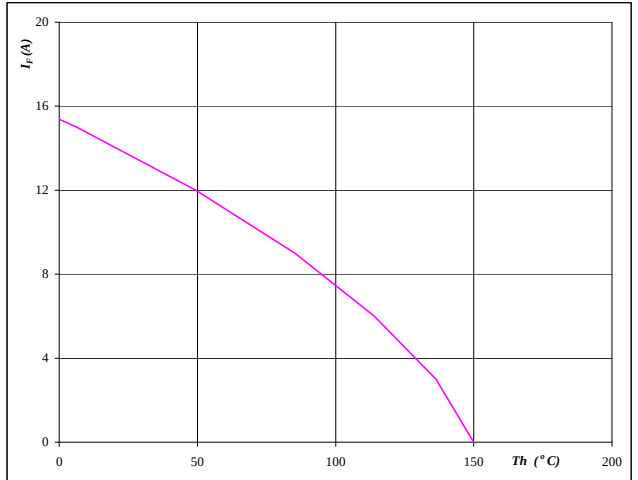


At
 $T_j = 150 \text{ °C}$

Figure 4 Boost IGBT Protection Diode

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



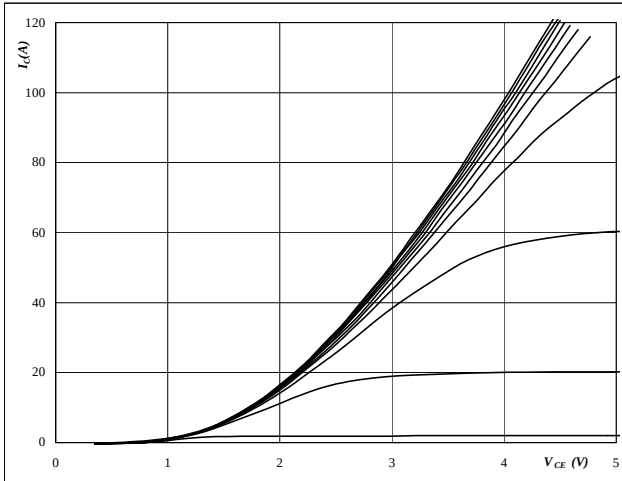
At
 $T_j = 150 \text{ °C}$

INPUT BOOST

Figure 3 BOOST IGBT

Typical output characteristics

$$I_D = f(V_{DS})$$



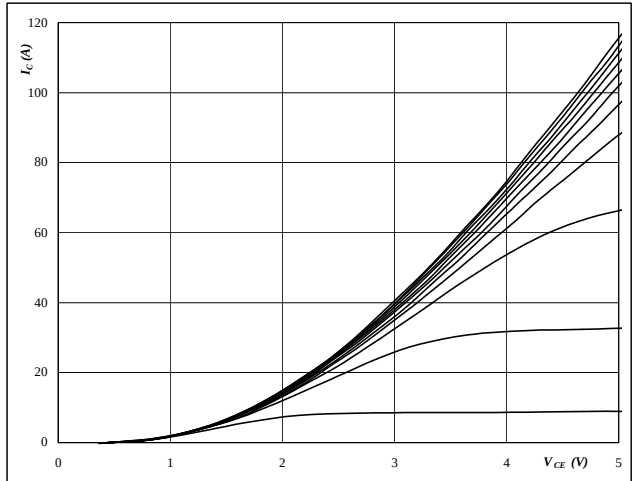
At

$t_p = 250 \mu s$
 $T_J = 25^\circ C$
 V_{GS} from 7 V to 17 V in steps of 1 V

Figure 4 BOOST FRED

Typical output characteristics

$$I_D = f(V_{DS})$$



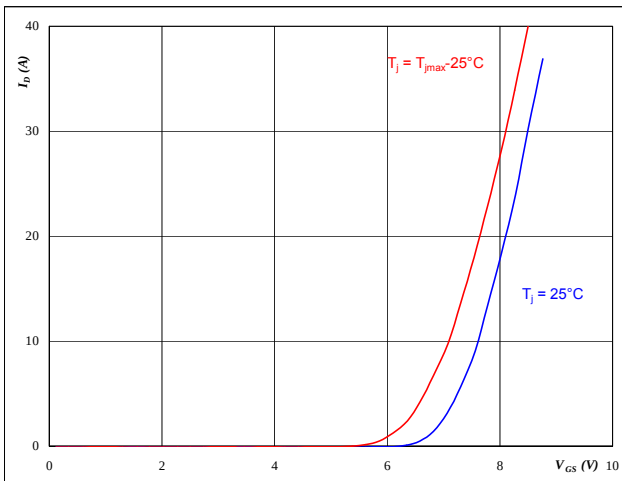
At

$t_p = 250 \mu s$
 $T_J = 125^\circ C$
 V_{GS} from 7 V to 17 V in steps of 1 V

Figure 3 BOOST IGBT

Typical transfer characteristics

$$I_D = f(V_{DS})$$



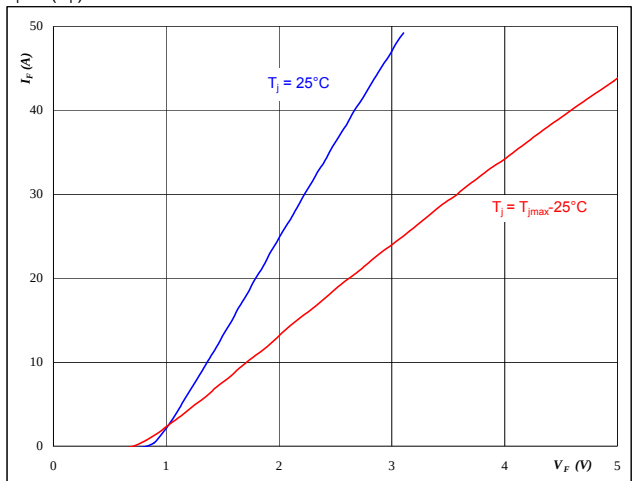
At

$t_p = 250 \mu s$
 $V_{DS} = 10 V$

Figure 4 BOOST FRED

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$



At

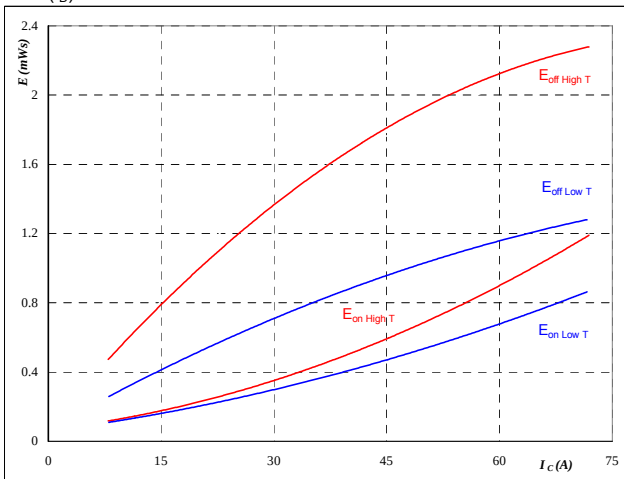
$t_p = 250 \mu s$

INPUT BOOST

Figure 5 BOOST IGBT

Typical switching energy losses
as a function of collector current

$$E = f(I_D)$$



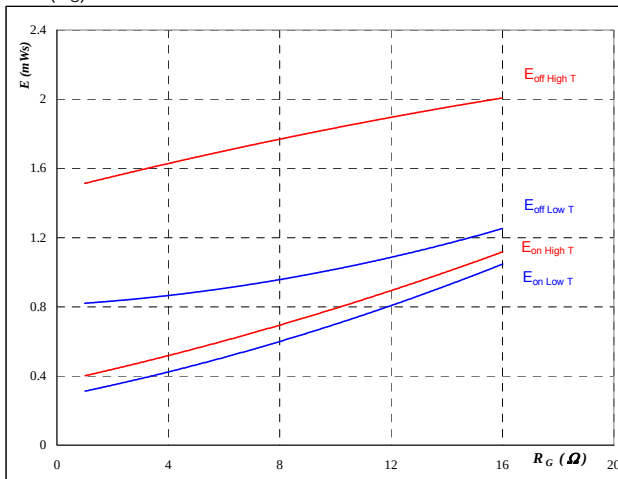
With an inductive load at

$T_J = 25/125 \text{ } ^\circ\text{C}$
 $V_{DS} = 600 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$
 $R_{goff} = 4 \text{ } \Omega$

Figure 6 BOOST IGBT

Typical switching energy losses
as a function of gate resistor

$$E = f(R_G)$$



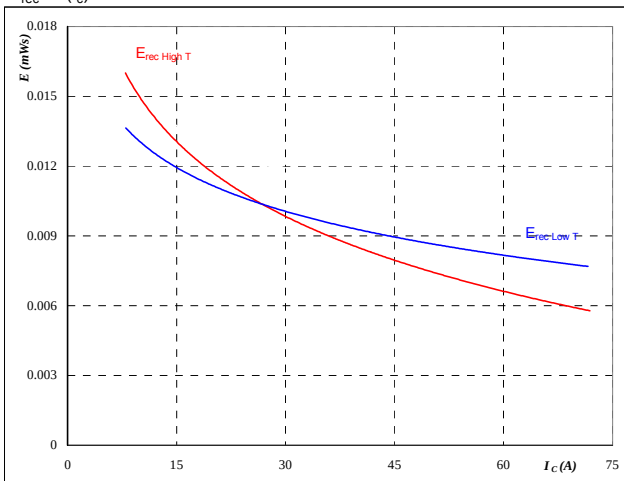
With an inductive load at

$T_J = 25/125 \text{ } ^\circ\text{C}$
 $V_{DS} = 600 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $I_D = 40 \text{ A}$

Figure 7 BOOST IGBT

Typical reverse recovery energy loss
as a function of collector (drain) current

$$E_{rec} = f(I_C)$$



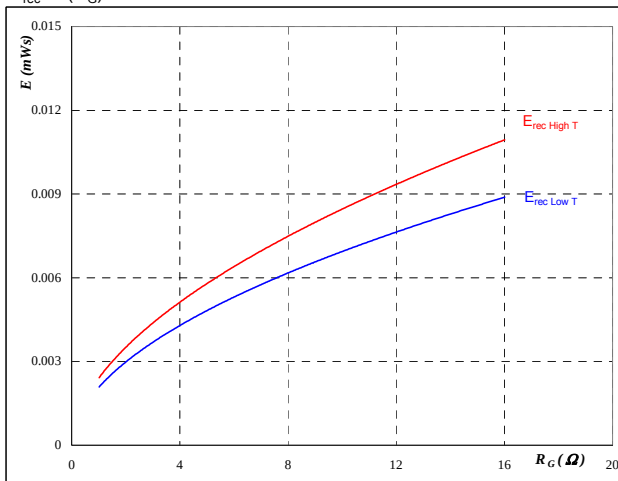
With an inductive load at

$T_J = 25/125 \text{ } ^\circ\text{C}$
 $V_{DS} = 600 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 8 BOOST IGBT

Typical reverse recovery energy loss
as a function of gate resistor

$$E_{rec} = f(R_G)$$



With an inductive load at

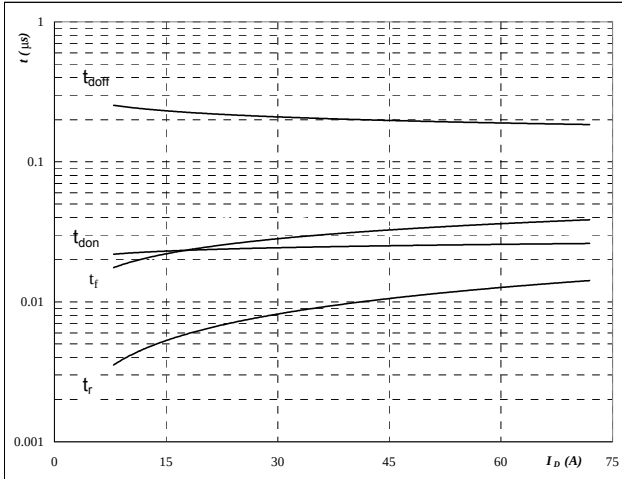
$T_J = 25/125 \text{ } ^\circ\text{C}$
 $V_{DS} = 600 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $I_D = 40 \text{ A}$

INPUT BOOST

Figure 9 BOOST IGBT

Typical switching times as a function of collector current

$$t = f(I_D)$$



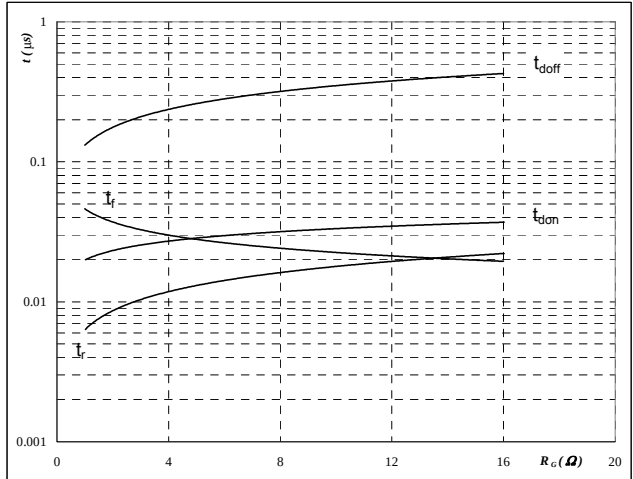
With an inductive load at

$T_J =$	125	°C
$V_{DS} =$	600	V
$V_{GS} =$	15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

Figure 10 BOOST IGBT

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



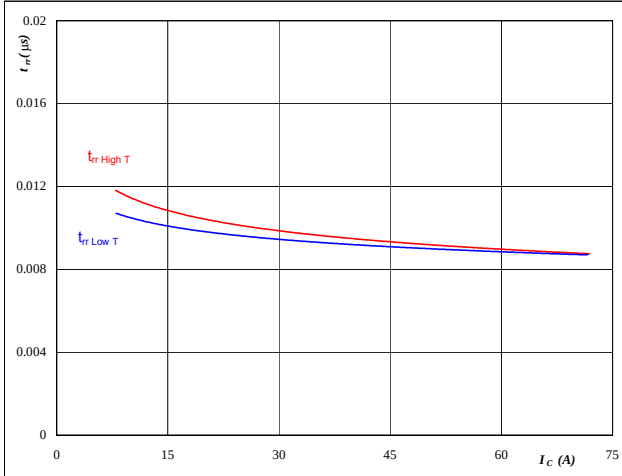
With an inductive load at

$T_J =$	125	°C
$V_{DS} =$	600	V
$V_{GS} =$	15	V
$I_C =$	40	A

Figure 11 BOOST FRED

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



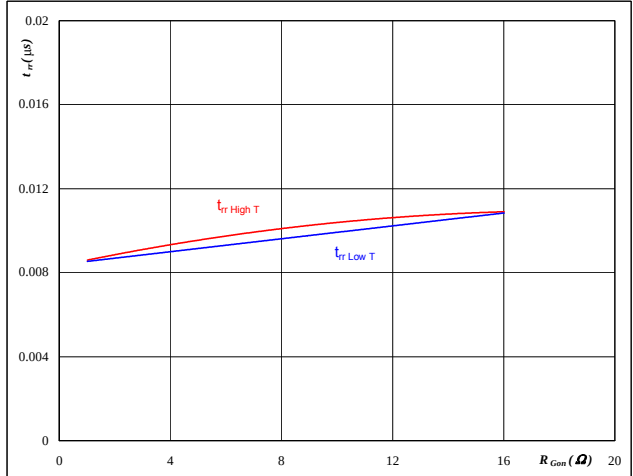
At

$T_J =$	25/125	°C
$V_{CE} =$	600	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 12 BOOST FRED

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{gon})$$



At

$T_J =$	25/125	°C
$V_R =$	600	V
$I_F =$	40	A
$V_{GS} =$	15	V

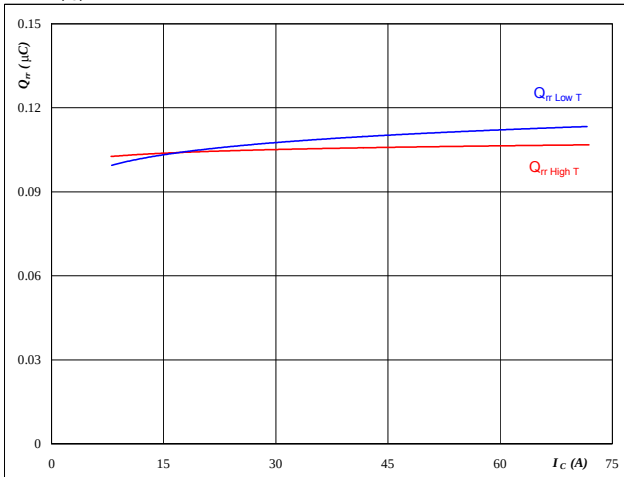
INPUT BOOST

Figure 13

BOOST FRED

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$



At

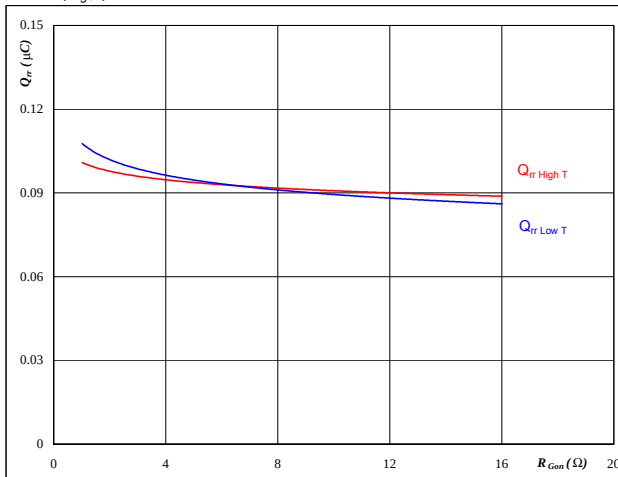
$T_J =$	25/125	°C
$V_{CE} =$	600	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 14

BOOST FRED

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$



At

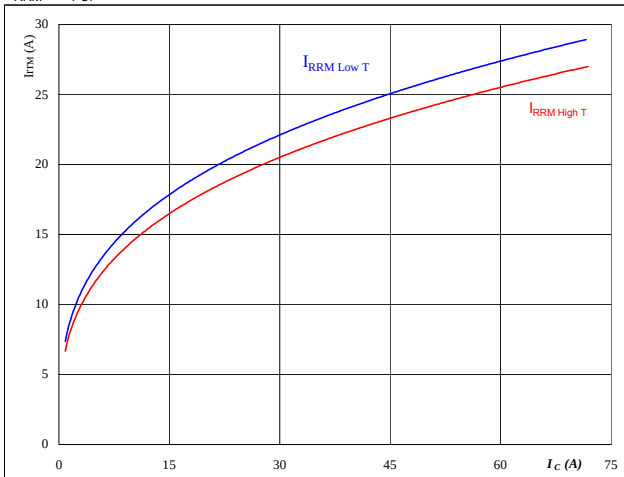
$T_J =$	25/125	°C
$V_R =$	600	V
$I_F =$	40	A
$V_{GS} =$	15	V

Figure 15

BOOST FRED

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$



At

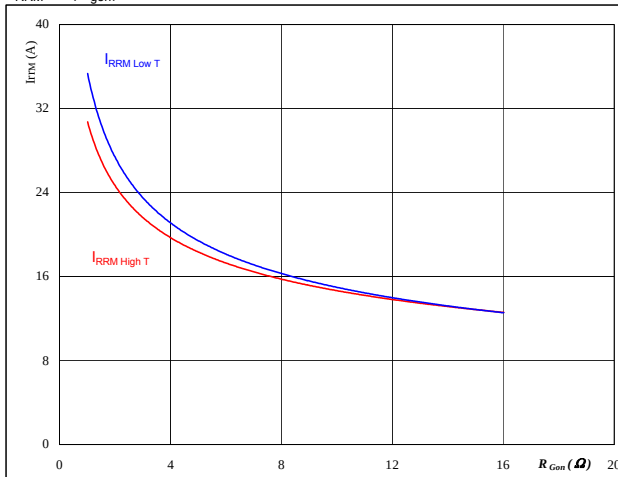
$T_J =$	25/125	°C
$V_{CE} =$	600	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 16

BOOST FRED

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At

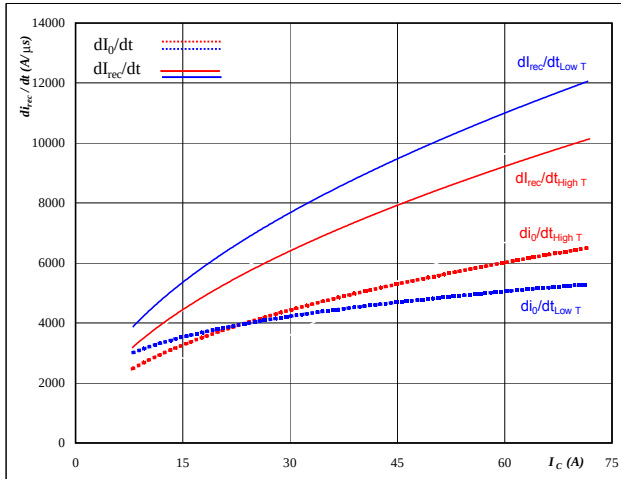
$T_J =$	25/125	°C
$V_R =$	600	V
$I_F =$	40	A
$V_{GS} =$	15	V

INPUT BOOST

Figure 17 BOOST FRED

Typical rate of fall of forward
and reverse recovery current as a
function of collector current

$$dI_o/dt, dI_{rec}/dt = f(I_c)$$



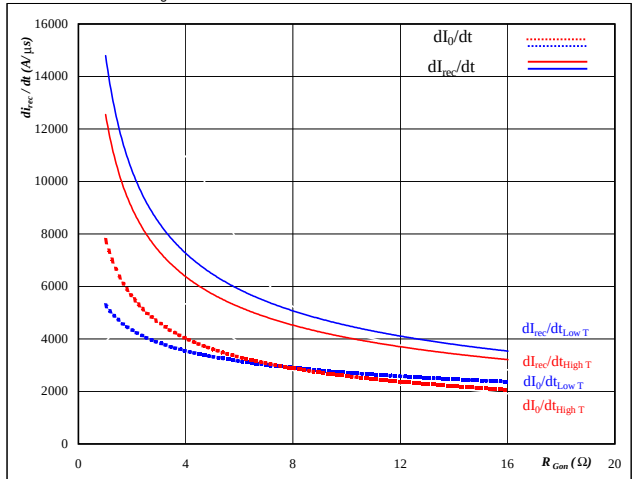
At

$T_j =$	25/125	°C
$V_{CE} =$	600	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 18 BOOST FRED

Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor

$$dI_o/dt, dI_{rec}/dt = f(R_{gon})$$



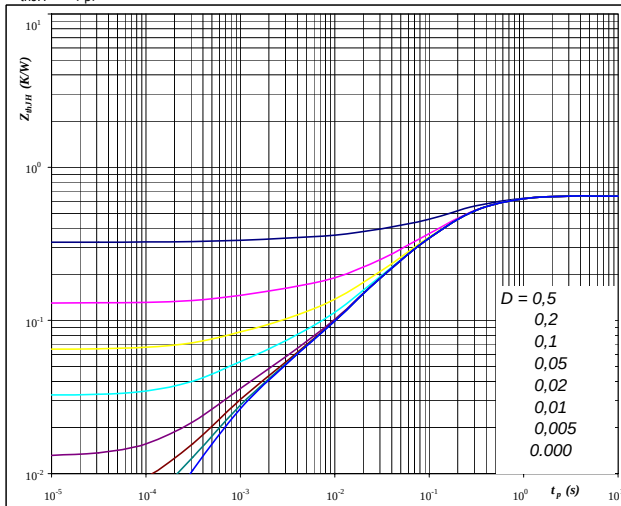
At

$T_j =$	25/125	°C
$V_R =$	600	V
$I_F =$	40	A
$V_{GS} =$	15	V

Figure 19 BOOST IGBT

IGBT/MOSFET transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At

$D =$	t_p / T	
$R_{thJH} =$	0.65	K/W

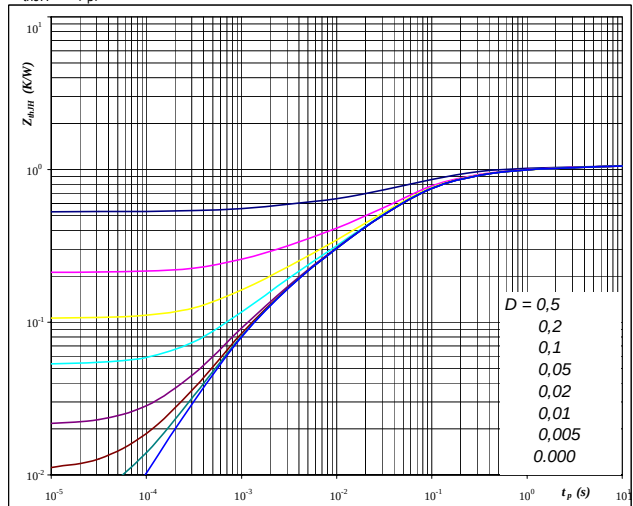
IGBT thermal model values

R (C/W)	Tau (s)
0.1982	0.4954
0.3469	0.1114
0.07537	0.01455
0.02798	0.0009603
0.02697	0.004091
0.03879	0.0003081

Figure 20 BOOST FRED

FRED transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At

$D =$	t_p / T	
$R_{thJH} =$	1.06	K/W

FRED thermal model values

R (C/W)	Tau (s)
0.06292	3.888
0.1803	0.398
0.5248	0.0619
0.2026	0.009365
0.08858	0.001177

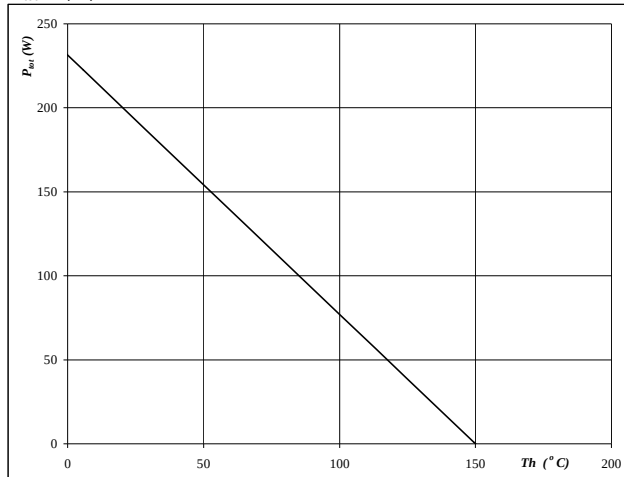
INPUT BOOST

Figure 21

BOOST IGBT

Power dissipation as a
function of heatsink temperature

$$P_{tot} = f(T_h)$$



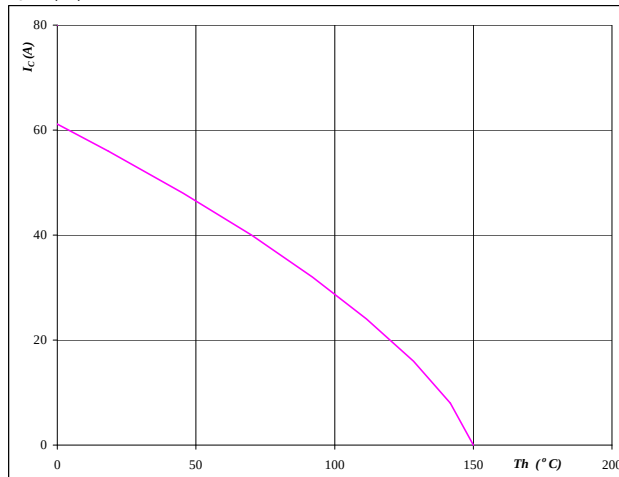
At
 $T_j = 150$ °C

Figure 22

BOOST IGBT

Collector/Drain current as a
function of heatsink temperature

$$I_C = f(T_h)$$



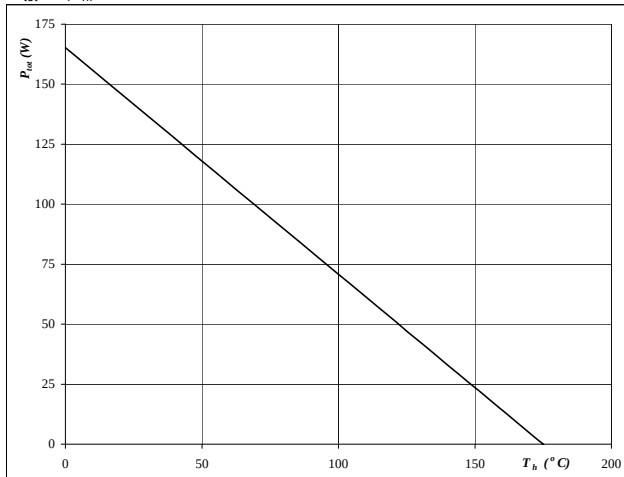
At
 $T_j = 150$ °C
 $V_{GS} = 15$ V

Figure 23

BOOST FRED

Power dissipation as a
function of heatsink temperature

$$P_{tot} = f(T_h)$$



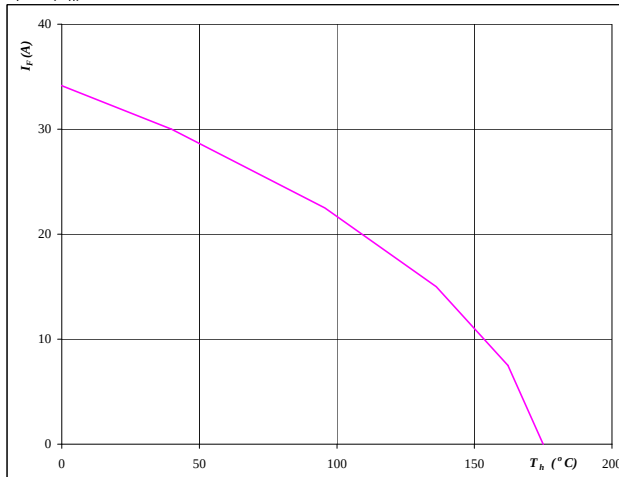
At
 $T_j = 175$ °C

Figure 24

BOOST FRED

Forward current as a
function of heatsink temperature

$$I_F = f(T_h)$$



At
 $T_j = 175$ °C

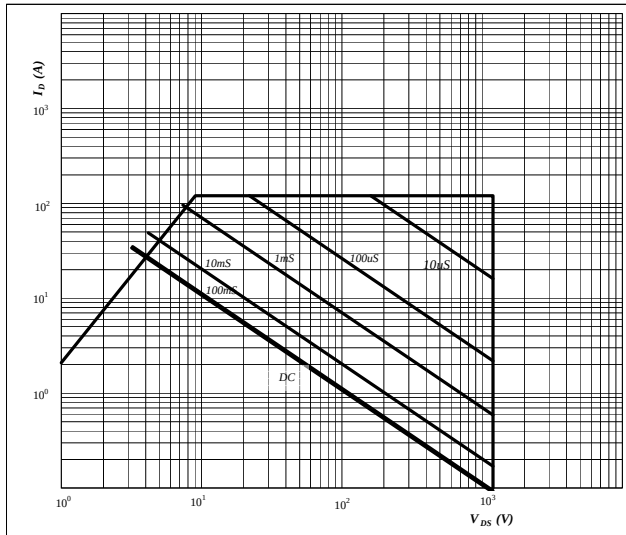
INPUT BOOST

Figure 25

BOOST IGBT

Safe operating area as a function
of drain-source voltage

$$I_D = f(V_{DS})$$



At

D = single pulse

$T_n = 80$ °C

$V_{GS} = 15$ V

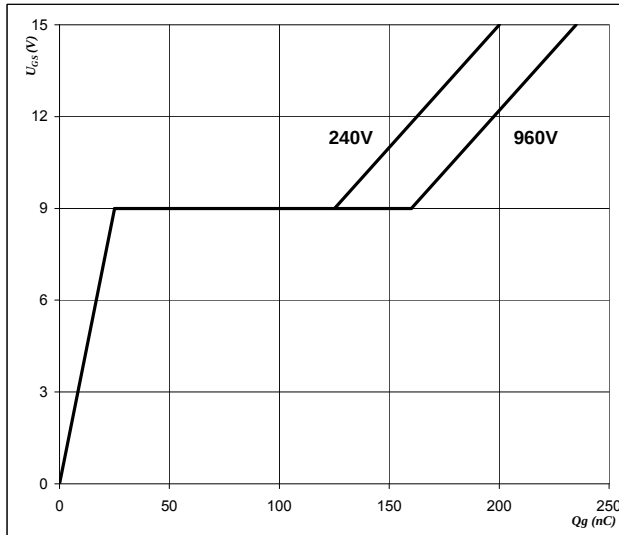
$T_j = T_{jmax}$ °C

Figure 26

BOOST IGBT

Gate voltage vs Gate charge

$$V_{GS} = f(Q_g)$$



At

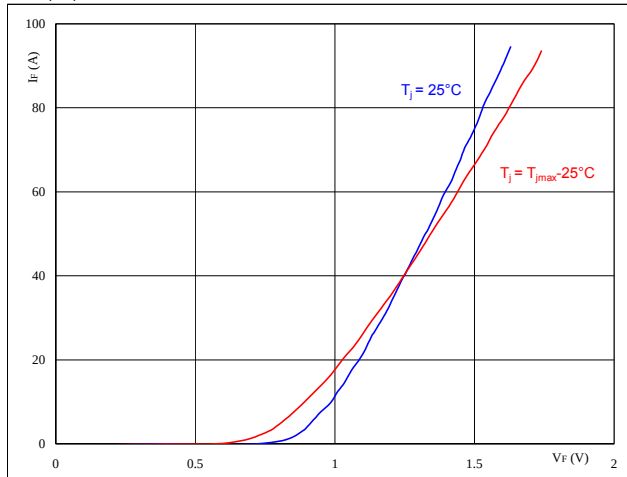
$I_D = 40$ A

Bypass Diode

Figure 1 Bypass diode

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

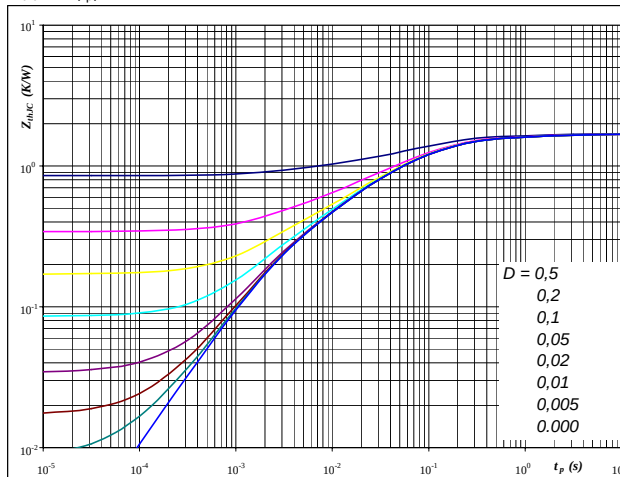


At
 $t_p = 250 \mu s$

Figure 2 Bypass diode

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$

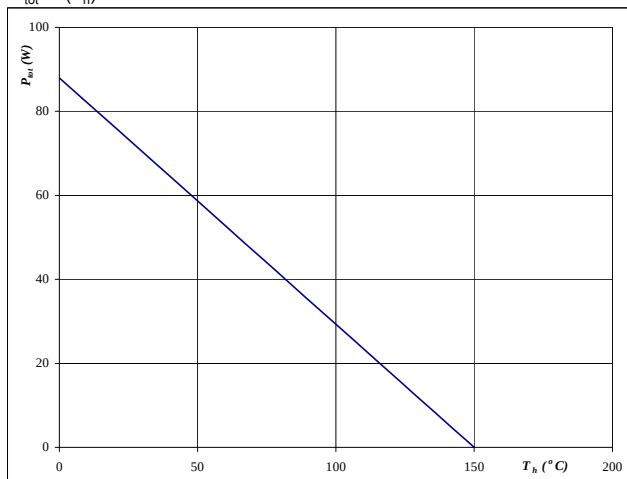


At
 $D = t_p / T$
 $R_{thJH} = 1.705 \text{ K/W}$

Figure 3 Bypass diode

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

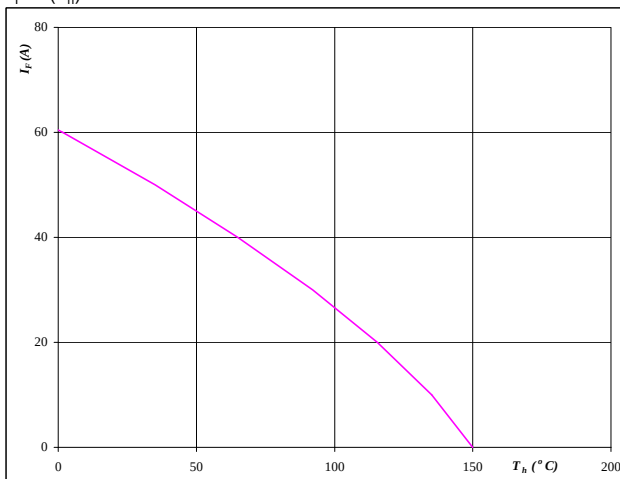


At
 $T_j = 150 \text{ °C}$

Figure 4 Bypass diode

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



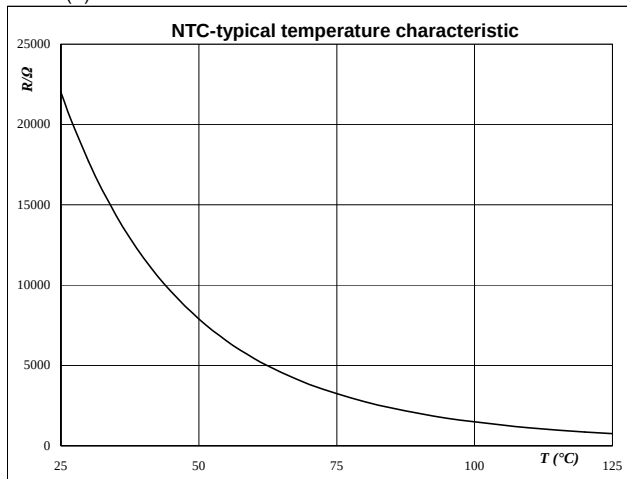
At
 $T_j = 150 \text{ °C}$

Thermistor

Figure 1 Thermistor

Typical NTC characteristic
as a function of temperature

$$R_T = f(T)$$



Switching Definitions BUCK MOSFET

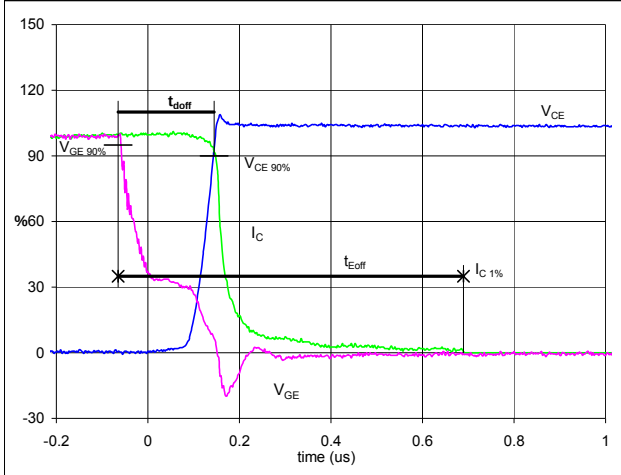
General conditions

T_j	=	125 °C
R_{gon}	=	4 Ω
R_{goff}	=	4 Ω

Figure 1 Output inverter IGBT

Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}

(t_{Eoff} = integrating time for E_{off})

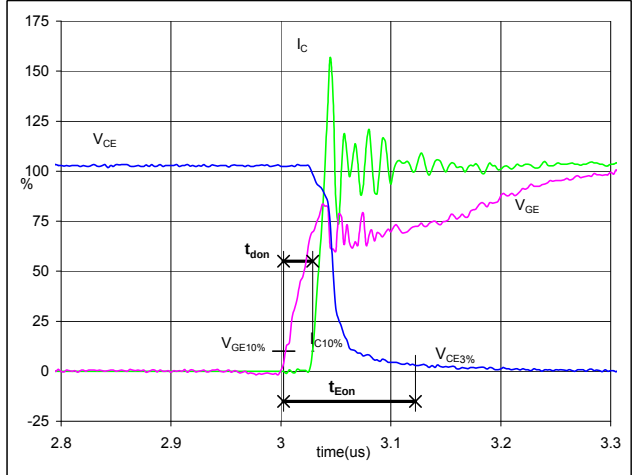


$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	15	V
$V_C(100\%) =$	600	V
$I_C(100\%) =$	40	A
$t_{doff} =$	0.20	μs
$t_{Eoff} =$	0.75	μs

Figure 2 Output inverter IGBT

Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}

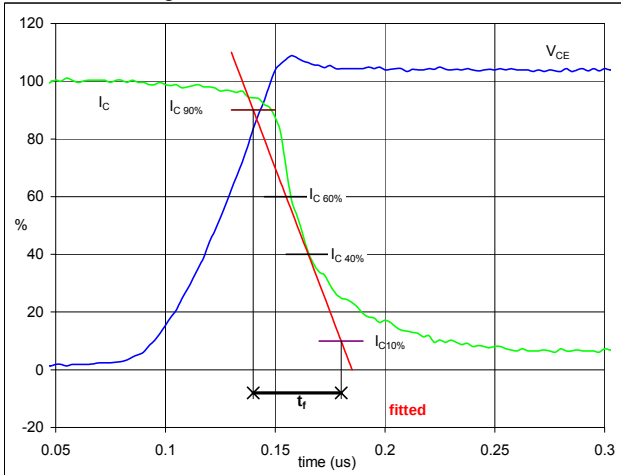
(t_{Eon} = integrating time for E_{on})



$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	15	V
$V_C(100\%) =$	600	V
$I_C(100\%) =$	40	A
$t_{don} =$	0.03	μs
$t_{Eon} =$	0.12	μs

Figure 3 Output inverter IGBT

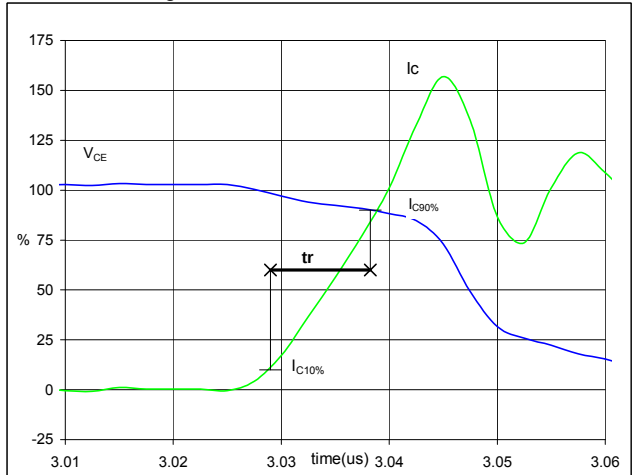
Turn-off Switching Waveforms & definition of t_f



$V_C(100\%) =$	600	V
$I_C(100\%) =$	40	A
$t_f =$	0.04	μs

Figure 4 Output inverter IGBT

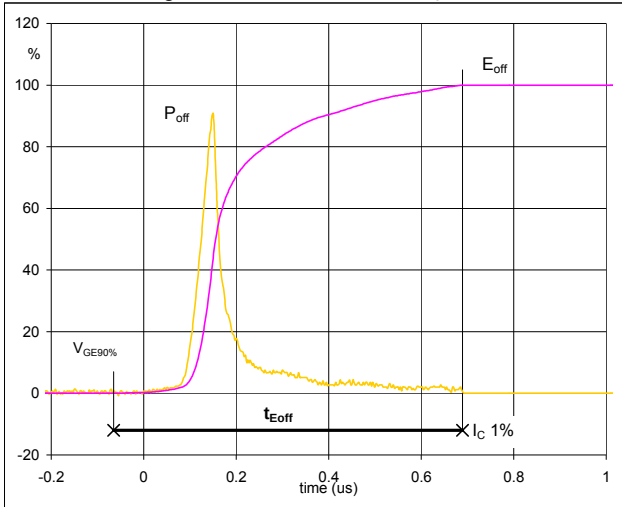
Turn-on Switching Waveforms & definition of t_r



$V_C(100\%) =$	600	V
$I_C(100\%) =$	40	A
$t_r =$	0.01	μs

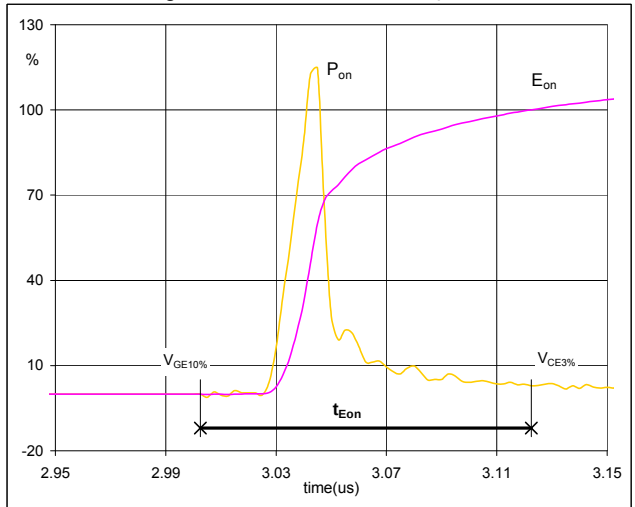
Switching Definitions BUCK MOSFET

Figure 5 Output inverter IGBT
Turn-off Switching Waveforms & definition of t_{Eoff}



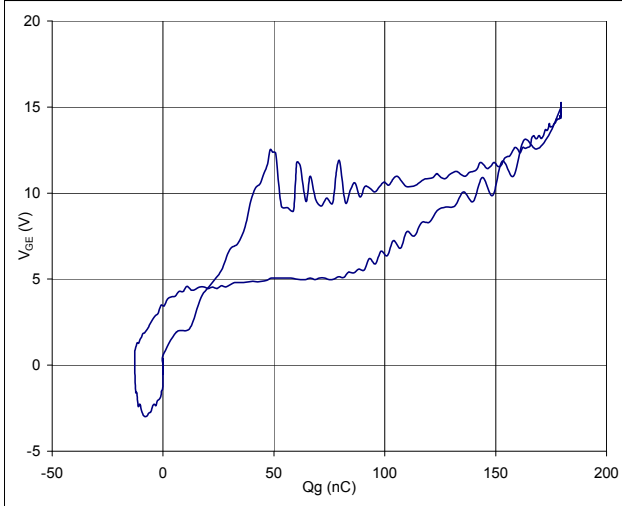
$P_{off}(100\%) = 24.06$ kW
 $E_{off}(100\%) = 1.66$ mJ
 $t_{Eoff} = 0.75$ μ s

Figure 6 Output inverter IGBT
Turn-on Switching Waveforms & definition of t_{Eon}



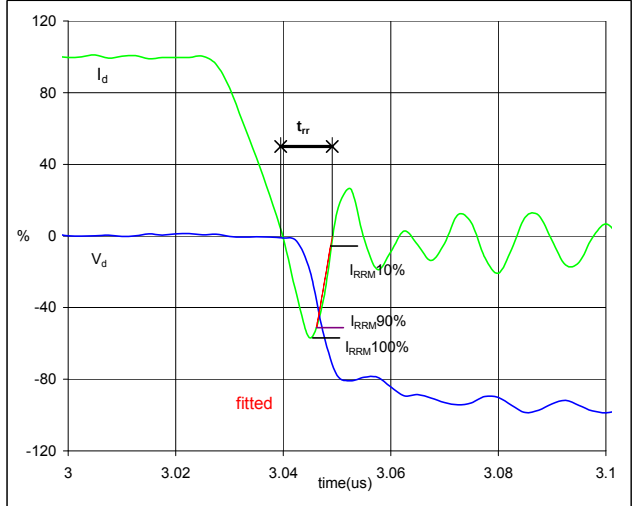
$P_{on}(100\%) = 24.06$ kW
 $E_{on}(100\%) = 0.51$ mJ
 $t_{Eon} = 0.12$ μ s

Figure 7 Output inverter FRED
Gate voltage vs Gate charge (measured)



$V_{GEoff} = 0$ V
 $V_{GEon} = 15$ V
 $V_C(100\%) = 600$ V
 $I_C(100\%) = 40$ A
 $Q_g = 179.55$ nC

Figure 8 Output inverter IGBT
Turn-off Switching Waveforms & definition of t_{rr}

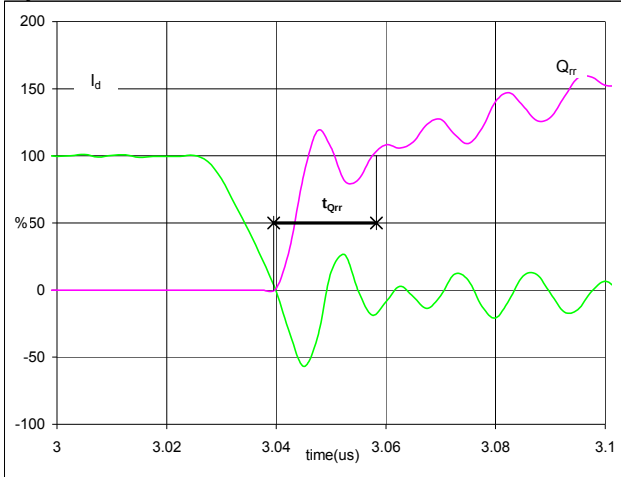


$V_d(100\%) = 600$ V
 $I_d(100\%) = 40$ A
 $I_{RRM}(100\%) = -23$ A
 $t_{rr} = 0.01$ μ s

Switching Definitions BUCK IGBT

Figure 9 Output inverter FRED

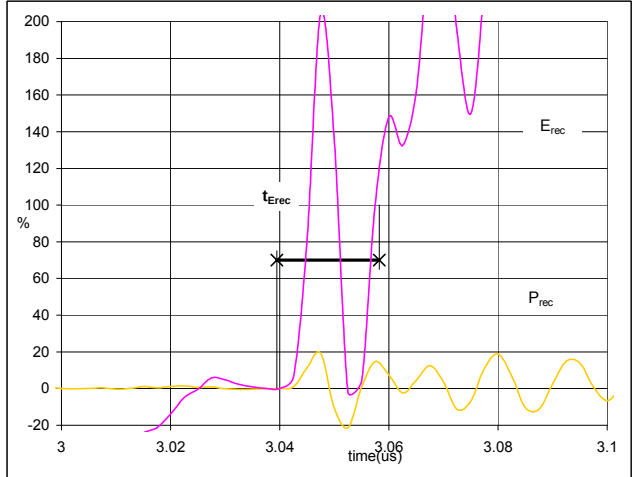
Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})



I_d (100%) = 40 A
 Q_{rr} (100%) = 0.11 μ C
 t_{Qrr} = 0.02 μ s

Figure 10 Output inverter FRED

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



P_{rec} (100%) = 24.06 kW
 E_{rec} (100%) = 0.01 mJ
 t_{Erec} = 0.02 μ s

Measurement circuits

Figure 11

BUCK stage switching measurement circuit

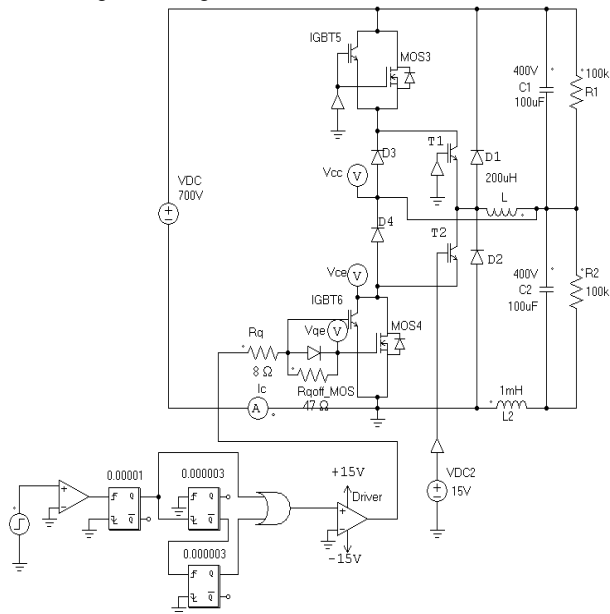
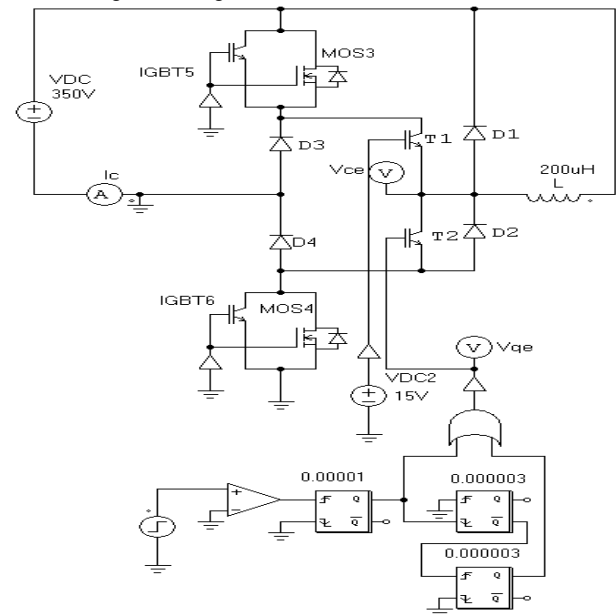


Figure 12

BOOST stage switching measurement circuit



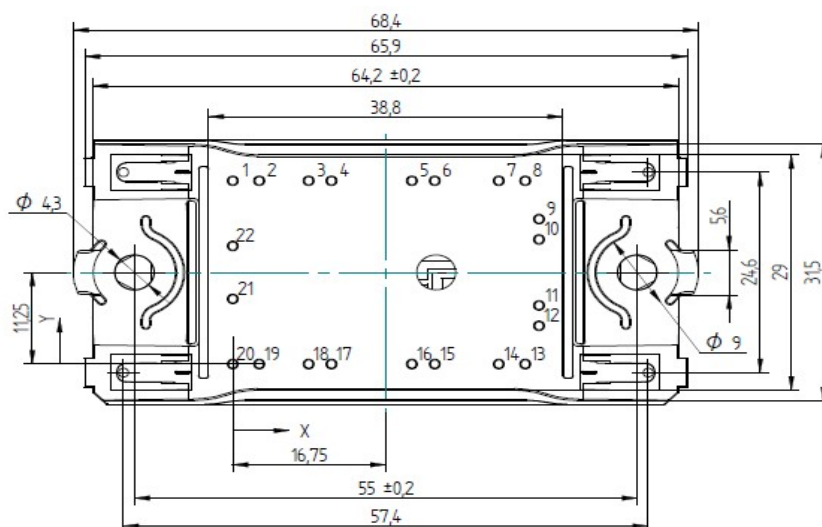
Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking

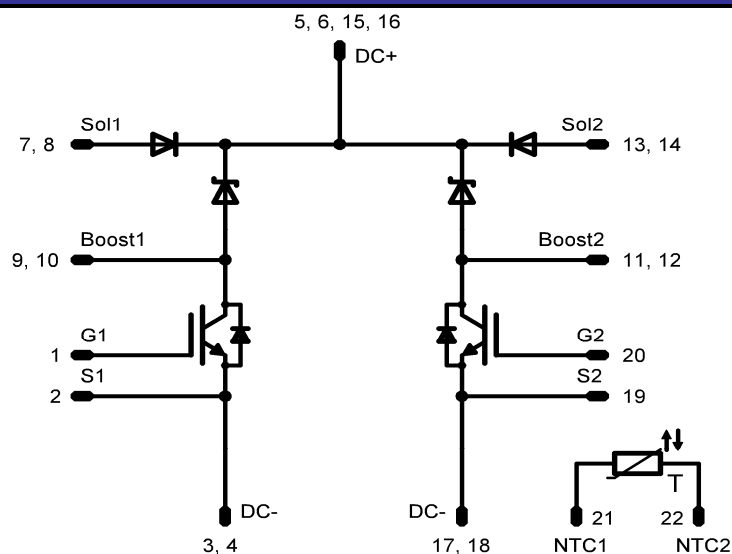
Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 12mm housing	V23990-P629-F62-PM	P629-F62	P629-F62
without thermal paste 17mm housing	V23990-P629-F629-PM	P629-F629	P629-F62
without thermal paste 12mm housing with PressFiT	V23990-P629-F628Y-PM	P629-F628Y	P629-F628Y
without thermal paste 17mm housing with PressFiT	V23990-P629-F629Y-PM	P629-F629Y	P629-F629Y

Outline

Pin table		
Pin	X	Y
1	0	22,5
2	2,9	22,5
3	8,3	22,5
4	10,8	22,5
5	19,6	22,5
6	22,1	22,5
7	29,1	22,5
8	32	22,5
9	33,5	17,8
10	33,5	15,3
11	33,5	7,2
12	33,5	4,7
13	32	0
14	29,1	0
15	22,1	0
16	19,6	0
17	10,8	0
18	8,3	0
19	2,9	0
20	0	0
21	0	8
22	0	14,5



Pinout



PRODUCT STATUS DEFINITIONS

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data may be published at a later date. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.
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